Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/600,637	HAYNER ET AL.
Examiner	Art Unit

Kim-Kwok CHU

2627

SEARCHED					
Class	Subclass	Date	Examiner		
369	44.26	4/25/2007	кс		
369	53.28	4/25/2007	кс		
369	44.36	4/25/2007	кс		
369	44.27	4/25/2007	кс		
369	53.23	4/25/2007	кс		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH (INCLUDING SEAF		·)
	DATE	EXMR
East Search Updated	4/25/2007	кс
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